Supervised Machine Learning Review

Outline

by Paul Hand Northeastern University

Regression + Classification Problems Statistical Framework for ML Justification for Square loss & Cross entropy loss Bias Variance Trade off, model selection, an unexpected twist

Common Problems in Supervised ML

Regression :predict a continuous valueLet $f: \mathbb{R}^d \rightarrow \mathbb{R}$ y = f(x) + noiseGiven: $\{(x_{i}, y_i)\}_{i=1\cdots n}^{d}$ Find :f



Terminology o

$$\chi$$
 - input variables, predictors, independent vars, features
 Y - response, dependent variable, output variable
 f - model, predictor, hypothesis

Statistical Framework for ML (supervised)

Assume:

•
$$(X_1Y)$$
 are sampled from a joint probability distribution
• Training data $D = \{(X_i, Y_i)\}_{i=1\cdots n}$ are iid samples
• Test data are also iid samples

Can estimate the model/predictor by maximum likelihood estimation

Results (vsvally) in an optimization problem

$$\widehat{f} = \operatorname{argmin} \sum_{i=1}^{n} l(f(X_i), y_i)$$

$$\widehat{f} \in \mathcal{H}$$

wh*ere*

$$\&$$
 ~ loss function eg $\& (\hat{y}, y) = |\hat{y} - y|^2$
 \mathcal{H} - hypothesis class eg degree d polynomial

Linear Regression and Square Loss Let $a \in \mathbb{R}^{d}$, $x \in \mathbb{R}^{d}$ Model: $y_{i} = \chi_{i}^{t}a + \varepsilon_{i}$ $\forall \varepsilon_{i} \sim \mathcal{N}(0, \sigma^{2})$ Data: $D = \xi (x_{i}, y_{i}) \Im_{i=1} \dots n$

Estimate a by maximum likelihood

$$pdf$$
 of \mathcal{E}_i is $\frac{1}{\sqrt{2\pi}\sigma}e^{-\frac{Z^2}{2\sigma^2}}$ over $Z \in \mathbb{R}$
likelihood of data (using $\mathcal{E}_i = y_i - \chi_i^t a$)
 $L(a) = \prod_{i=1}^n \frac{1}{\sqrt{2\pi}\sigma}e^{-(y_i - \chi_i^t a)^2/2\sigma^2}$
 $\log L(a) = -\sum_{i=1}^n \frac{(y_i - \chi_i^t a)^2}{2\sigma^2} + terms constant in a$
maximizing data likelihood \iff minimizing square loss

$$\max_{a} L(a) \iff \min_{\substack{i=1\\ a}} \sum_{\substack{i=1\\ i=1\\ i=1}}^{n} (\chi_{i}^{t}a - y_{i})^{2}$$

$$square loss \ l(\hat{y}_{i}y) = |\hat{y} - y|^{2}$$

Logistic Regression and Cross Entropy Loss



Cross entropy loss

$$\mathcal{L}_{CE}(P, q) = -\sum_{Z \in \mathbb{Z}} P(Z) \log Q(Z) = -\mathbb{E}(\log q)$$

 $discrete$
 $f.v.s over \mathbb{Z}$

 $\begin{array}{c} \text{Maximizing dato likelihood} \iff \min inimizing \text{ cross entropy loss} \\ \max_{a} L(a) \iff \min_{a} -\sum_{i=1}^{n} \left(y_i \log \left(\sigma(x_i^{\dagger a}) \right) + (1-y_i) \log(1-\sigma(x_i^{\dagger a})) \right) \\ R_{CE} \left(\left(\begin{pmatrix} y_i \\ 1-y_i \end{pmatrix}, \begin{pmatrix} \sigma(x_i^{\dagger a}) \\ 1-\sigma(x_i^{\dagger a}) \end{pmatrix} \right) \end{array}$

Note:

Question to ponder[®] Is minimizing Cross Entropy loss all that different from minimizing a square loss in the case of regression? Bias-Voriance Tradeoff

What class of hypotheses should you search over? Standard Statistical ML story: error test error training error model complexity Bias - Variance Decomposition Kenter Statistical ML story: higher complexity models higher variance If complexity is boo high, it oversits data, variance term dominates test error after a certain threshold, "larger models are worse"

Consider regression model y = f(x) + E $W \in E[E|X] = 0$ Let $D = \{(x_{i_1}y_i)\}_{i=1\cdots n}$ be iid samples Estimate f by an algorithm producing \hat{f}_D Evaluate \hat{f}_D by expected loss on a new sample $R(\hat{f}_D) = E_{x_1y} (\hat{f}_D(x) - y)^2$ risk $\frac{\text{test}}{\text{sample}} \frac{\text{square loss}}{\text{square loss}}$ Performance will vary based on D. Take expectation over D. $E_D R(\hat{f}_D) = E_{x_1y,D} (\hat{f}_D(x) - y)^2$

We will decompose into 3 effects: bias, vorionce, irreducible

$$\mathbb{E}_{D} R(\hat{f}) = \mathbb{E}_{\chi_{1}y_{1}D} \left[\left(\hat{f}_{D}(\chi) - f(\chi) - \varepsilon \right)^{2} \right]$$

$$= \mathbb{E}_{\chi_{1}y_{1}D} \left(\hat{f}_{D}(\chi) - f(\chi) \right)^{2} - 2 \mathbb{E} \left[\left(\hat{f}_{D}(\chi) - f(\chi) \right) \varepsilon \right] + \mathbb{E} \left[\varepsilon^{2} \right]$$

$$= \mathbb{E}_{\chi_{1}y_{1}D} \left(\hat{f}_{D}(\chi) - f(\chi) \right)^{2} + Var(\varepsilon)$$

$$Var(\varepsilon)$$

Evaluating the first term, Conditioning on X, $\mathbb{E}_{\mathcal{D}}\left(\widehat{f}_{\mathcal{D}}(\boldsymbol{x}) - \widehat{f}(\boldsymbol{x})\right)^{2} = \mathbb{E}_{\mathcal{D}}\left[\left(\widehat{f}_{\mathcal{D}}(\boldsymbol{x}) - \mathbb{E}_{\mathcal{D}}\widehat{f}_{\mathcal{D}}(\boldsymbol{x})\right) + \left(\mathbb{E}_{\mathcal{D}}\widehat{f}_{\mathcal{D}}(\boldsymbol{x}) - \widehat{f}(\boldsymbol{x})\right)\right]^{2}\right]$ $= \mathbb{E}_{\mathcal{D}}\left(\hat{f}_{\mathcal{D}}(\boldsymbol{x}) - \mathbb{E}_{\mathcal{D}}\hat{f}_{\mathcal{D}}(\boldsymbol{x})\right)^{2} + 2\mathbb{E}_{\mathcal{D}}\left(\hat{f}_{\mathcal{D}}(\boldsymbol{x}) - \mathbb{E}_{\mathcal{D}}\hat{f}_{\mathcal{D}}(\boldsymbol{x})\right) \left(\mathbb{E}_{\mathcal{D}}\hat{f}_{\mathcal{D}}(\boldsymbol{x}) - \boldsymbol{f}(\boldsymbol{x})\right) + \mathbb{E}_{\mathcal{D}}\left(\mathbb{E}_{\mathcal{D}}\hat{f}_{\mathcal{D}}(\boldsymbol{x}) - \boldsymbol{f}(\boldsymbol{x})\right)^{2}$ O in expectation does not depend in D $= \mathbb{E}_{\mathcal{D}} \left(\hat{f}_{\mathcal{D}}(\boldsymbol{x}) - \mathbb{E}_{\mathcal{D}} \hat{f}_{\mathcal{D}}(\boldsymbol{x}) \right)^{2} + \left(\mathbb{E}_{\mathcal{D}} \left(\hat{f}_{\mathcal{D}}(\boldsymbol{x}) - f(\boldsymbol{x}) \right) \right)^{2}$ squared bias Variance of \$-p(2) So, $\mathbb{E}_{\mathcal{D}} \mathbb{R}(\hat{f}) = \mathbb{E}_{\mathcal{V}} \left(f(\mathbf{x}) - \mathbb{E}_{\mathcal{D}} \hat{f}_{\mathcal{D}}(\mathbf{x}) \right)^2 + \mathbb{E}_{\mathcal{X}} V_{\mathcal{O}_{\mathcal{D}}} \hat{f}_{\mathcal{D}}(\mathbf{x}) + V_{\mathcal{O}_{\mathcal{O}}}(\mathbf{x})$ expected squared bias expected variance irreducible of estimate GILOY of estimate Illustration of bias variance tradeoff Suppose y = X + E Low complexity model of y= C $\mathbb{E}_{\chi}(f(\chi) - \mathbb{E}_{\mathcal{D}}\hat{f}_{\mathcal{D}})^{2}$ is high E, Var, for(x) is low

High complexity model & y= Co+C1 x + C2 x2 + -- Ce x6 $\mathbb{E}_{\chi} \left(f(\chi) - \mathbb{E}_{D} \hat{f}_{D} \right)^{2} \text{ is low}$ $\mathbb{E}_{\chi} \operatorname{Var}_{D} \hat{f}_{D}(\chi) \text{ is high}$



higher complexity models have lower bigs but higher variance

If complexity is boo high, it oversits data, variance term dominates test Error

after a certain threshold, "lorger models are worse"

Modern Story based on Neural Nets:



Test error can decrease as model complexity continues increasing,

And it can be lower than in underparameterized regime

Phenomenon: double descent